BYV32E-200

Dual rugged ultrafast rectifier diode, 20 A, 200 V

Rev. 04 — 27 February 2009

Product data sheet

1. Product profile

1.1 General description

Ultrafast dual epitaxial rectifier diode in a SOT78 (TO-220AB) plastic package.

1.2 Features and benefits

- High reverse voltage surge capability
- High thermal cycling performance
- Low thermal resistance

- Soft recovery characteristic minimizes power consuming oscillations
- Very low on-state loss

1.3 Applications

 Output rectifiers in high-frequency switched-mode power supplies

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{RRM}	repetitive peak reverse voltage		-	-	200	V
$I_{O(AV)}$	average output current	square-wave pulse; δ = 0.5; $T_{mb} \le 115$ °C; both diodes conducting; see <u>Figure 1</u> ; see <u>Figure 2</u>	-	-	20	Α
I _{RRM}	repetitive peak reverse current	$t_p=2~\mu s;\delta=0.001$	-	-	0.2	Α
V_{ESD}	electrostatic discharge voltage	HBM; C = 250 pF; R = 1.5 $k\Omega$; all pins	-	-	8	kV
Dynamic	characteristics					
t _{rr}	reverse recovery time	$I_F = 1 \text{ A}$; $V_R = 30 \text{ V}$; $dI_F/dt = 100 \text{ A/}\mu\text{s}$; $T_j = 25 ^{\circ}\text{C}$; ramp recovery; see Figure 5	-	20	25	ns
		I_R = 1 A; I_F = 0.5 A; T_j = 25 °C; step recovery; measured at reverse current = 0.25 A; see Figure 6	-	10	20	ns
Static ch	aracteristics					
V _F	forward voltage	$I_F = 8 \text{ A}; T_j = 150 \text{ °C}; \text{ see}$ Figure 4	-	0.72	0.85	V





2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	A1	anode 1		
2	K	cathode	mb	A1
3	A2	anode 2		<u> </u>
mb	К	mounting base; cathode	1 2 3	sym125
			SOT78	

(TO-220AB;SC-46)

3. Ordering information

Table 3. Ordering information

Type number	Package			
	Name	Description	Version	
BYV32E-200	TO-220AB; SC-46	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78	

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{RRM}	repetitive peak reverse voltage		-	200	V
V_{RWM}	crest working reverse voltage		-	200	V
V_R	reverse voltage	DC	-	200	V
I _{O(AV)}	average output current	square-wave pulse; δ = 0.5; $T_{mb} \le 115$ °C; both diodes conducting; see <u>Figure 1</u> ; see <u>Figure 2</u>	-	20	Α
I _{FRM}	repetitive peak forward current	δ = 0.5; t_p = 25 μ s; $T_{mb} \le$ 115 °C; per diode	-	20	Α
I _{FSM}	non-repetitive peak forward current	t_p = 8.3 ms; sine-wave pulse; $T_{j(init)}$ = 25 °C; per diode	-	137	Α
		t_p = 10 ms; sine-wave pulse; $T_{j(init)}$ = 25 °C; per diode	-	125	Α
I _{RRM}	repetitive peak reverse current	$\delta = 0.001$; $t_p = 2 \mu s$	-	0.2	Α
I _{RSM}	non-repetitive peak reverse current	$t_p = 100 \ \mu s$	-	0.2	Α
T _{stg}	storage temperature		-40	150	°C
T _j	junction temperature		-	150	°C
V _{ESD}	electrostatic discharge voltage	HBM; C = 250 pF; R = 1.5 k Ω ; all pins	-	8	kV

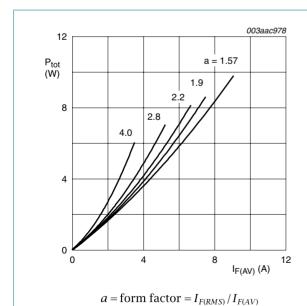


Fig 1. Forward power dissipation as a function of average forward current; sinusoidal waveform; maximum values

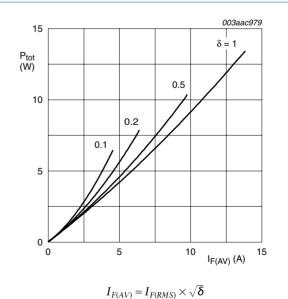


Fig 2. Forward power dissipation as a function of average forward current; square waveform; maximum values

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5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting	with heatsink compound; both diodes conducting	-	-	1.6	K/W
	base	with heatsink compound; per diode; see Figure 3	-	-	2.4	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient		-	60	-	K/W

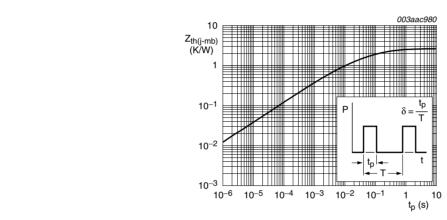


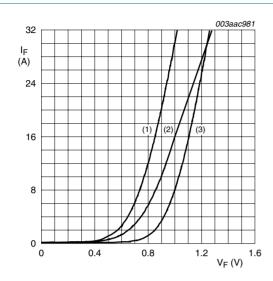
Fig 3. Transient thermal impedance from junction to mounting base as a function of pulse width

6. Characteristics

Table 6. Characteristics

Parameter	Conditions	Min	Тур	Max	Unit
aracteristics					
forward voltage	I _F = 20 A; T _j = 25 °C	-	1	1.15	V
	$I_F = 8 \text{ A}; T_j = 150 \text{ °C}; \text{ see } \frac{\text{Figure 4}}{\text{Minimum 1}}$	-	0.72	0.85	٧
reverse current	$V_R = 200 \text{ V}; T_j = 100 \text{ °C}$	-	0.2	0.6	mΑ
	V _R = 200 V; T _j = 25 °C	-	6	30	μΑ
characteristics					
recovered charge	$I_F = 2 \text{ A}$; $V_R = 30 \text{ V}$; $dI_F/dt = 20 \text{ A/}\mu\text{s}$; $T_j = 25 \text{ °C}$	-	8	12.5	nC
reverse recovery time	$I_F = 1$ A; $V_R = 30$ V; $dI_F/dt = 100$ A/ μ s; ramp recovery; $T_j = 25$ °C; see Figure 5	-	20	25	ns
	$I_F = 0.5 \text{ A}$; $I_R = 1 \text{ A}$; step recovery; measured at reverse current = 0.25 A; $T_j = 25 ^{\circ}\text{C}$; see Figure 6	-	10	20	ns
forward recovery voltage	I_F = 1 A; dI_F/dt = 10 A/ μ s; T_j = 25 °C; see Figure 7	-	-	1	V
	forward voltage reverse current characteristics recovered charge reverse recovery time	forward voltage $I_F = 20 \text{ A; } T_j = 25 \text{ °C}$ $I_F = 8 \text{ A; } T_j = 150 \text{ °C; see } \underline{\text{Figure 4}}$ $\text{reverse current} \qquad V_R = 200 \text{ V; } T_j = 100 \text{ °C}$ $V_R = 200 \text{ V; } T_j = 25 \text{ °C}$ characteristics $\text{recovered charge} \qquad I_F = 2 \text{ A; } V_R = 30 \text{ V; dI}_F/\text{dt} = 20 \text{ A/μs; } T_j = 25 \text{ °C}$ $\text{reverse recovery time} \qquad I_F = 1 \text{ A; } V_R = 30 \text{ V; dI}_F/\text{dt} = 100 \text{ A/μs; } \text{ramp recovery; } T_j = 25 \text{ °C; see } \underline{\text{Figure 5}}$ $I_F = 0.5 \text{ A; } I_R = 1 \text{ A; step recovery; } \text{measured at reverse current} = 0.25 \text{ A; } T_j = 25 \text{ °C; see } \underline{\text{Figure 6}}$ $\text{forward recovery} \qquad I_F = 1 \text{ A; dI}_F/\text{dt} = 10 \text{ A/μs; } T_j = 25 \text{ °C; see}$	forward voltage $I_F = 20 \text{ A; } T_j = 25 \text{ °C} \qquad - \\ I_F = 8 \text{ A; } T_j = 150 \text{ °C; see } \underline{\text{Figure 4}} \qquad - \\ \text{reverse current} \qquad V_R = 200 \text{ V; } T_j = 100 \text{ °C} \qquad - \\ \hline V_R = 200 \text{ V; } T_j = 25 \text{ °C} \qquad - \\ \hline \text{characteristics} \qquad \\ \text{recovered charge} \qquad I_F = 2 \text{ A; } V_R = 30 \text{ V; dI}_F/\text{dt} = 20 \text{ A/}\mu\text{s; } \qquad - \\ \hline T_j = 25 \text{ °C} \qquad \\ \text{reverse recovery time} \qquad I_F = 1 \text{ A; } V_R = 30 \text{ V; dI}_F/\text{dt} = 100 \text{ A/}\mu\text{s; } \qquad - \\ \hline I_F = 0.5 \text{ A; } I_R = 1 \text{ A; step recovery; } \qquad - \\ \hline I_F = 0.5 \text{ A; } I_R = 1 \text{ A; step recovery; } \qquad - \\ \hline I_F = 25 \text{ °C; see } \underline{\text{Figure 6}} \qquad - \\ \hline \text{forward recovery} \qquad I_F = 1 \text{ A; dI}_F/\text{dt} = 10 \text{ A/}\mu\text{s; } T_j = 25 \text{ °C; see} \qquad - \\ \hline $	forward voltage $I_F = 20 \text{ A; } T_j = 25 \text{ °C} \qquad \qquad - \qquad 1$ $I_F = 8 \text{ A; } T_j = 150 \text{ °C; see Figure 4} \qquad - \qquad 0.72$ $reverse \ current \qquad V_R = 200 \text{ V; } T_j = 100 \text{ °C} \qquad - \qquad 0.2$ $V_R = 200 \text{ V; } T_j = 25 \text{ °C} \qquad - \qquad 6$ $characteristics$ $recovered \ charge \qquad I_F = 2 \text{ A; } V_R = 30 \text{ V; } dI_F/dt = 20 \text{ A/μs;} \qquad - \qquad 8$ $T_j = 25 \text{ °C}$ $reverse \ recovery \ time \qquad I_F = 1 \text{ A; } V_R = 30 \text{ V; } dI_F/dt = 100 \text{ A/μs;} \qquad - \qquad 20$ $ramp \ recovery; T_j = 25 \text{ °C; see Figure 5}$ $I_F = 0.5 \text{ A; } I_R = 1 \text{ A; step recovery;} \qquad - \qquad 10$ $measured \ at \ reverse \ current = 0.25 \text{ A;}$ $T_j = 25 \text{ °C; see Figure 6}$ $forward \ recovery \qquad I_F = 1 \text{ A; } dI_F/dt = 10 \text{ A/μs; } T_j = 25 \text{ °C; see} \qquad - \qquad -$	$ \begin{array}{c} \text{forward voltage} & I_F = 20 \text{ A; } T_j = 25 \text{ °C} & - & 1 & 1.15 \\ I_F = 8 \text{ A; } T_j = 150 \text{ °C; see } \underline{\text{Figure 4}} & - & 0.72 & 0.85 \\ \hline \text{reverse current} & V_R = 200 \text{ V; } T_j = 100 \text{ °C} & - & 0.2 & 0.6 \\ \hline V_R = 200 \text{ V; } T_j = 25 \text{ °C} & - & 6 & 30 \\ \hline \text{characteristics} & \\ \hline \text{recovered charge} & I_F = 2 \text{ A; } V_R = 30 \text{ V; } dI_F/dt = 20 \text{ A/}\mu\text{s; } & - & 8 & 12.5 \\ \hline T_j = 25 \text{ °C} & \\ \hline \text{reverse recovery time} & I_F = 1 \text{ A; } V_R = 30 \text{ V; } dI_F/dt = 100 \text{ A/}\mu\text{s; } & - & 20 & 25 \\ \hline I_F = 0.5 \text{ A; } I_R = 1 \text{ A; step recovery; } & - & 10 & 20 \\ \hline \text{measured at reverse current} = 0.25 \text{ A; } \\ \hline T_j = 25 \text{ °C; see } \underline{\text{Figure 6}} & \\ \hline \text{forward recovery} & I_F = 1 \text{ A; } dI_F/dt = 10 \text{ A/}\mu\text{s; } T_j = 25 \text{ °C; see} & - & - & 1 \\ \hline \end{array}$





- (1) $T_j = 150$ °C; typical values
- (2) $T_j = 150$ °C; maximum values
- (3) $T_j = 25$ °C; maximum values

Fig 4. Forward current as a function of forward voltage

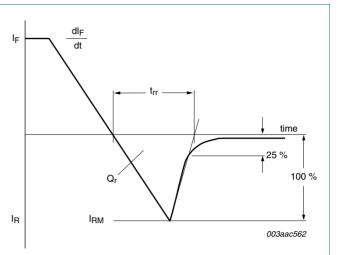


Fig 5. Reverse recovery definitions; ramp recovery

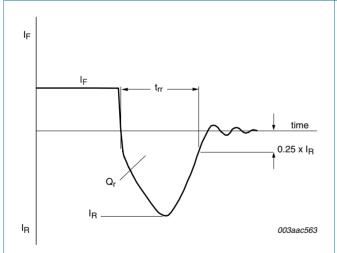


Fig 6. Reverse recovery definitions; step recovery

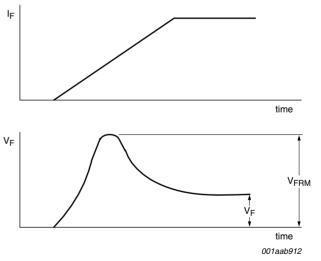
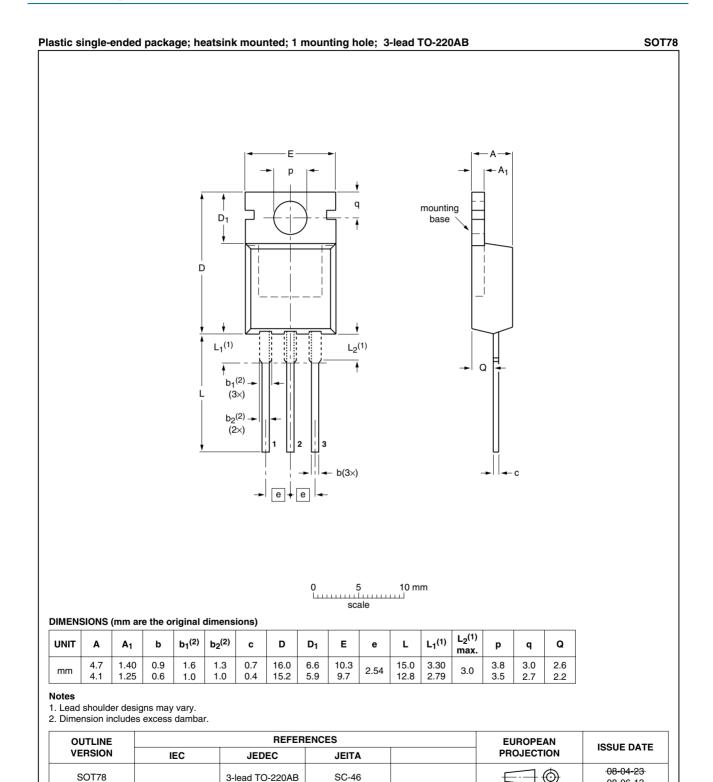


Fig 7. Forward recovery definitions

Package outline



Package outline SOT78 (TO-220AB)

08-06-13



8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BYV32E-200_4	20090227	Product data sheet	-	BYV32E_SERIES_3
Modifications:		of this data sheet has been of NXP Semiconductors.	n redesigned to comply w	ith the new identity
	 Legal texts 	have been adapted to the	new company name whe	re appropriate.
	 Package or 	utline updated.		
	 Type numb 	er BYV32E-200 separated	from data sheet BYV32E	_SERIES_3
BYV32E_SERIES_3	20010301	Product specification	-	BYV32E_SERIES_2
BYV32E_SERIES_2	19980701	Product specification	-	BYV32EB_SERIES_1
BYV32EB_SERIES_1	19960801	Product specification	-	-

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9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
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